Fundamentals of Quantitative Design and Analysis

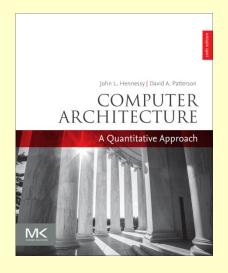
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CS-4515, System Programming Concepts

(Slides include copyright materials from Computer Architecture: A Quantitative Approach, 5th ed., by Hennessy and Patterson and from Computer Organization and Design, 4th ed. by Patterson and Hennessy)



Computer Architecture A Quantitative Approach, Sixth Edition



Chapter 1

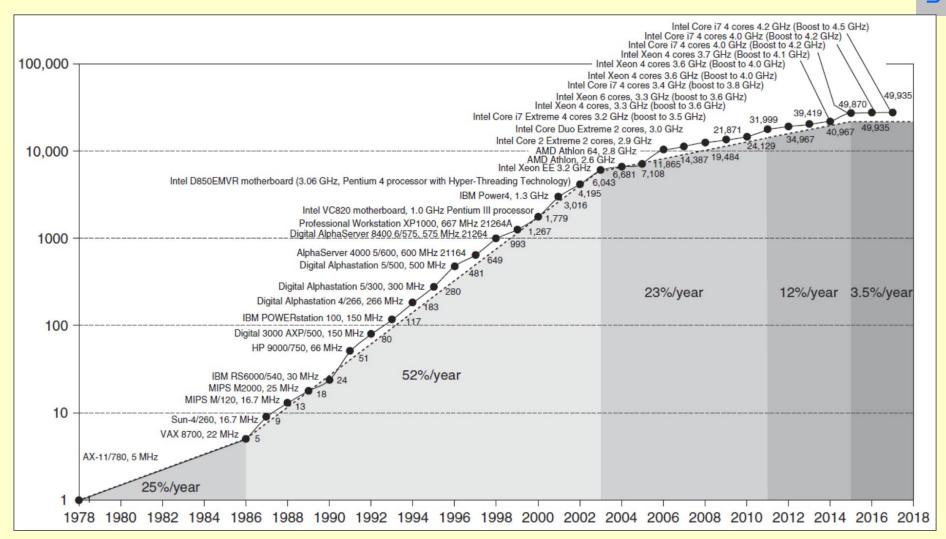
Fundamentals of Quantitative Design and Analysis

Computer Technology

Performance improvements:

- Improvements in semiconductor technology
 - Feature size, clock speed
- Improvements in computer architectures
 - Enabled by HLL compilers, UNIX
 - Lead to RISC architectures
- Together have enabled:
 - Lightweight computers
 - Productivity-based managed/interpreted programming languages

Single Processor Performance



Current Trends in Architecture

- Cannot continue to leverage Instruction-Level parallelism (ILP)
 - Single processor performance improvement ended in 2003
- New models for performance:
 - Data-level parallelism (DLP)
 - Thread-level parallelism (TLP)
 - Request-level parallelism (RLP)
- These require explicit restructuring of applications

Classes of Computers

Personal Mobile Device (PMD)

- e.g. start phones, tablet computers
- Emphasis on energy efficiency and real-time

Desktop Computing

Emphasis on price-performance

Servers

Emphasis on availability, scalability, throughput

Clusters / Warehouse Scale Computers

- Used for "Software as a Service (SaaS)"
- Emphasis on availability and price-performance
- Sub-class: Supercomputers, emphasis: floating-point performance and fast internal networks

Internet of Things/Embedded Computers

Emphasis: price

Parallelism

Classes of parallelism in applications:

- Data-Level Parallelism (DLP)
- Task-Level Parallelism (TLP)

Classes of architectural parallelism:

- Instruction-Level Parallelism (ILP)
- Vector architectures/Graphic Processor Units (GPUs)
- Thread-Level Parallelism
- Request-Level Parallelism

Flynn's Taxonomy

- Single instruction stream, single data stream (SISD)
- Single instruction stream, multiple data streams (SIMD)
 - Vector architectures
 - Multimedia extensions
 - Graphics processor units
- Multiple instruction streams, single data stream (MISD)
 - No commercial implementation
- Multiple instruction streams, multiple data streams (MIMD)
 - Tightly-coupled MIMD
 - Loosely-coupled MIMD

These are key terms for all Computer Science topics.

Defining Computer Architecture

- "Traditional" view of computer architecture:—
 - Instruction Set Architecture (ISA) design
 - i.e. decisions regarding:
 - registers, memory addressing, addressing modes, instruction operands, available operations, control flow instructions, instruction encoding

"Real" computer architecture:

- Specific requirements of the target machine
- Design to maximize performance within constraints:
 cost, power, and availability
- Includes ISA, microarchitecture, hardware

Use

Saver

Instruction Set Architecture (ISA)

- Classes of ISA
 - General-purpose registers
 - Register-memory vs load-store
- RISC-V registers

32 g.p., 32 f.p.

				x9	s1	saved	callee
Register	Name	Use	Saver	x10-x17	a0-a7	arguments	caller
х0	zero	constant 0	n/a	x18-x27	s2-s11	saved	callee
x1	ra	return addr	caller	x28-x31	t3-t6	temporaries	caller
x2	sp	stack ptr	callee	f0-f7	ft0-ft7	FP temps	caller
х3	gp	gbl ptr		f8-f9	fs0-fs1	FP saved	callee
х4	tp	thread ptr		f10-f17	fa0-fa7	FP arguments	callee
x5-x7	t0-t2	temporaries	caller				
x8	s0/fp	saved/	callee	f18-f27	fs2-fs21	FP saved	callee
	50, p	frame ptr	Sunce	f28-f31	ft8-ft11	FP temps	caller

Register

Name

Instruction Set Architecture

Memory addressing

RISC-V: byte addressed, aligned accesses faster

Addressing modes

- RISC-V: Register, immediate, displacement (base+offset)
- Other examples: autoincrement, indexed, PC-relative

Types and size of operands

RISC-V: 8-bit, 32-bit, 64-bit

Instruction Set Architecture

Operations

- RISC-V: data transfer, arithmetic, logical, control, floating point
- See Fig. 1.5 in text

Control flow instructions

- Use content of registers (RISC-V) vs. status bits (x86, ARMv7, ARMv8)
- Return address in register (RISC-V, ARMv7, ARMv8) vs. on stack (x86)

Encoding

 Fixed (RISC-V, ARMv7/v8 except compact instruction set) vs. variable length (x86)

Trends in Technology

- Integrated circuit technology (Moore's Law)
 - Transistor density: 35%/year
 - Die size: 10-20%/year
 - Integration overall: 40-55%/year
- DRAM capacity: 25-40%/year (slowing)
 - 8 Gb (2014), 16 Gb (2019), possibly no 32 Gb
- Flash capacity: 50-60%/year
 - 8-10X cheaper/bit than DRAM
- Magnetic disk capacity: recently slowed to 5%/year
 - Density increases may no longer be possible, maybe increase from 7 to 9 platters
 - 8-10X cheaper/bit then Flash
 - 200-300X cheaper/bit than DRAM

Bandwidth and Latency

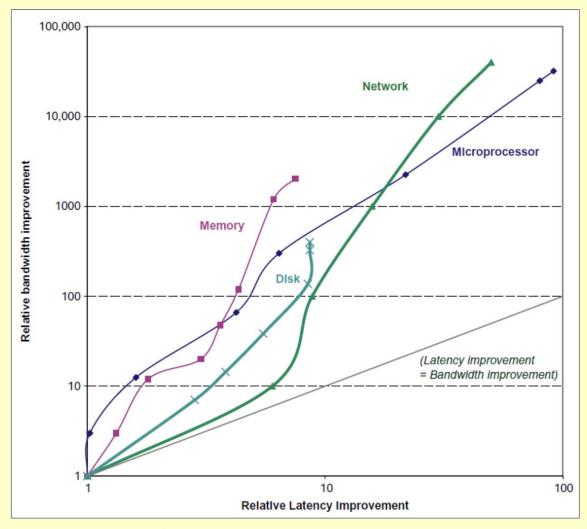
Bandwidth or throughput

- Total work done in a given time
- 32,000-40,000X improvement for processors
- 300-1200X improvement for memory and disks

Latency or response time

- Time between start and completion of an event
- 50-90X improvement for processors
- 6-8X improvement for memory and disks

Bandwidth and Latency



Log-log plot of bandwidth and latency milestones

Figure 1.9

Transistors and Wires

Feature size

- Minimum size of transistor or wire in x or y dimension
- 10 microns in 1971 to .011 microns in 2017
- Transistor performance scales linearly
 - Wire delay does not improve with feature size!
- Integration density scales quadratically

Power and Energy

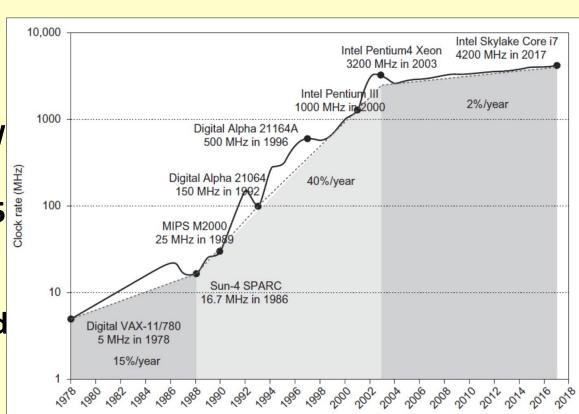
- Problem: Get power in, get power out
- Thermal Design Power (TDP)
 - Characterizes sustained power consumption
 - Used as target for power supply and cooling system
 - Lower than peak power (1.5X higher), higher than average power consumption
- Clock rate can be reduced dynamically to limit power consumption
- Energy per task is often a better measurement

Dynamic Energy and Power

- Dynamic energy
 - Transistor switch from 0 -> 1 or 1 -> 0
 - ½ x Capacitive load x Voltage²
- Dynamic power
 - ½ x Capacitive load x Voltage² x Frequency switched
- Reducing clock rate reduces power, not energy

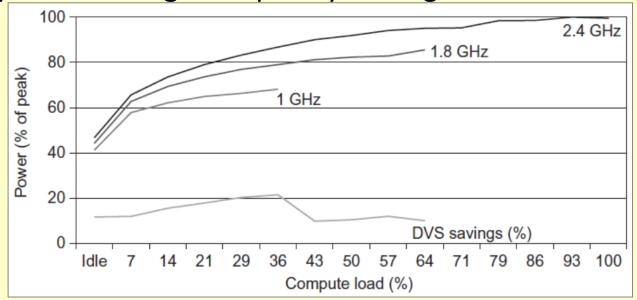
Power

- Intel 80386 consumed ~ 2 W
- 3.3 GHz Intel Corei7 consumes 130 W
- Heat must be dissipated from 1.5x 1.5 cm chip
- This is the limit of what can be cooled by air



Reducing Power

- Techniques for reducing power:—
 - Do nothing well
 - Dynamic Voltage-Frequency Scaling

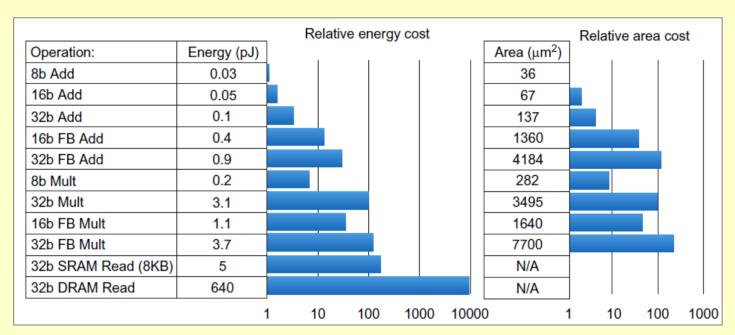


- Low power state for DRAM, disks
- Overclocking, turning off cores

Static Power

Static power consumption

- 25-50% of total power
- Current_{static} x Voltage
- Scales with number of transistors
- To reduce: power gating



Trends in Cost

- Cost driven down by learning curve
 - Yield
- DRAM: price closely tracks cost
- Microprocessors: price depends on volume
 - 10% less for each doubling of volume

Integrated Circuit Cost

Integrated circuit

$$\textit{Cost of integrated circuit} = \frac{\textit{Cost of die} + \textit{Cost of testing die} + \textit{Cost of packaging and final test}}{\textit{Final test yield}}$$

$$Cost \ of \ die = \frac{Cost \ of \ wafer}{Dies \ per \ wafer \ x \ Die \ yield}$$

$$\textit{Dies per wafer} = \frac{\pi \times (\textit{Wafer diameter}/2)^2}{\textit{Die area}} - \frac{\pi \times \textit{Wafer diameter}}{\sqrt{2 \times \textit{Die area}}}$$

Bose-Einstein formula:

Die yield = Waf er yield
$$\times 1/(1 + Defects per unit area \times Die area)^N$$

- Defects per unit area = 0.016-0.057 defects per square cm (2010)
- N = process-complexity factor = 11.5-15.5 (40 nm, 2010)

Section 1.6

Dependability

Module reliability

- Mean time to failure (MTTF)
- Mean time to repair (MTTR)
- Mean time between failures (MTBF) = MTTF + MTTR
- Availability = MTTF / MTBF

Measuring Performance

Typical performance metrics:

- Response time
- Throughput

Speedup of X relative to Y

Execution time_Y / Execution time_X

Execution time

- Wall clock time: includes all system overheads
- CPU time: only computation time

Benchmarks

- Kernels (e.g. matrix multiply)
- Toy programs (e.g. sorting)
- Synthetic benchmarks (e.g. Dhrystone)
- Benchmark suites (e.g. SPEC06fp, TPC-C)

Principles of Computer Design

Take Advantage of Parallelism

 e.g. multiple processors, disks, memory banks, pipelining, multiple functional units

Principle of Locality

Reuse of data and instructions

Focus on the Common Case

Amdahl's Law

$$Execution \ time_{new} = Execution \ time_{old} \times \left((1 - Fraction_{enhanced}) + \frac{Fraction_{enhanced}}{Speedup_{enhanced}} \right)$$

$$Speedup_{overall} = \frac{1}{(1 - Fraction_{enhanced}) + \frac{Fraction_{enhanced}}{Speedup_{enhanced}}}$$

Principles of Computer Design

The Processor Performance Equation

CPU time = CPU clock cycles for a program \times Clock cycle time

$$CPU time = \frac{CPU clock cycles for a program}{Clock rate}$$

$$CPI = \frac{CPU \ clock \ cycles \ for \ a \ program}{Instruction \ count}$$

CPU time = Instruction count \times Cycles per instruction \times Clock cycle time

$$\frac{Instructions}{Program} \times \frac{Clock\ cycles}{Instruction} \times \frac{Seconds}{Clock\ cycle} = \frac{Seconds}{Program} = CPU\ time$$

Principles of Computer Design

Different instruction types having different CPIs

$$CPU\ clock\ cycles\ = \sum_{i=1}^{n} IC_i \times CPI_i$$

$$CPU\ time = \left(\sum_{i=1}^{n} IC_{i} \times CPI_{i}\right) \times Clock\ cycle\ time$$

Fallacies and Pitfalls

All exponential laws must come to an end

- Dennard scaling (constant power density)
 - Stopped by threshold voltage
- Disk capacity
 - 30-100% per year to 5% per year
- Moore's Law
 - Most visible with DRAM capacity
 - ITRS disbanded
 - Only four foundries left producing state-of-the-art logic chips
 - 11 nm, 3 nm might be the limit

Fallacies and Pitfalls

- Microprocessors are a silver bullet
 - Performance is now a programmer's burden
- **■** Falling prey to Amdahl's Law
- A single point of failure
- Hardware enhancements that increase performance also improve energy efficiency, or are at worst energy neutral
- Benchmarks remain valid indefinitely
 - Compiler optimizations target benchmarks

Fallacies and Pitfalls

- The rated mean time to failure of disks is 1,200,000 hours or almost 140 years, so disks practically never fail
 - MTTF value from manufacturers assume regular replacement
- Peak performance tracks observed performance
- Fault detection can lower availability
 - Not all operations are needed for correct execution

Questions?